

Title (en)

Method of trimming thin metal resistors.

Title (de)

Verfahren zum Abgleichen von Metaldünnschichtwiderständen.

Title (fr)

Procédé pour ajuster des résistances à film mince en métal.

Publication

**EP 0055331 A2 19820707 (EN)**

Application

**EP 81107584 A 19810923**

Priority

US 22169580 A 19801231

Abstract (en)

A thin metal film resistor (15) of a capacitive graphic tablet is trimmed to make the resistor linear within about 0.25%. Alternating voltage is applied along the resistor by a source (40). The resistance of the resistor is measured at discrete points by a capacitive probe (34) and the resistance readings are stored in a data processor (45). A profile is calculated in the processor from the stored readings and a trim operation is made by an electro-erosion apparatus.

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IPC 8 full level

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